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Call for Papers

DFT is an annual Symposium providing an open forum for presentations in the field of defect and fault tolerance in VLSI systems inclusive of emerging technologies. One of the unique features of this symposium is to combine new academic research with state-of-the-art industrial data, necessary ingredients for significant advances in this field. All aspects of design, manufacturing, test, reliability, and availability that are affected by defects during manufacturing and by faults during system operation are of interest.

The topics include (but are not limited to) the following ones:

- Yield Analysis and Modeling**
Defect/Fault analysis and models; statistical yield modeling; critical area and metrics.
- Repair, Restructuring and Reconfiguration**
Repairable logic, reconfiguration, repair; reconfigurable circuit design; DFT for on-line operation.
- Testing Techniques**
Built-in self-test; delay fault modeling and diagnosis; testing for analog and mixed circuits; signal and clock integrity.
- Error Detection, Correction, and Recovery**
Self-testing and self-checking design; error-control coding; fault masking and avoidance; recovery schemes, space/time redundancy.
- Defect and Fault Tolerance**
Reliable circuit synthesis; radiation hardened/tolerant processes and design; transient/soft faults and errors.
- Dependability Analysis and Validation**
Fault injection techniques and environments; dependability characterization of IC and systems.
- Emerging Technologies**
DFT techniques for CNTs, QCA, DNA, RTDs, SETs, molecular devices and self-assembly.
- Design For Testability in IC Design**
FPGA, SoC, NoC, ASIC, microprocessors
- Totally Fail-Safe Design for Critical Applications**
Methodologies and case study applications to automotive, railway, avionics, industrial control, biomedicine and space.

Paper Submission: Prospective authors should prepare an extended summary or the full paper (up to 9 pages in the IEEE 6X9 format), to be submitted as PDF file. Uncompressed unencapsulated postscript may also be used when necessary. Submission should be done electronically. Detailed information about the submission process will be made available on the symposium web page:

<http://www.dfts.org>

We are also interested in panel sessions that involve industrial experiences: please send an email to the Program Chairs with a brief description (1 page maximum) of the panel discussion you would like to propose.

Paper Publication and Presenter Registration: Only *original, unpublished* work will be accepted, for regular or poster presentation at the symposium. Proceedings will be published by the IEEE Computer Society. Each accepted paper **MUST** have at least an author with a paid full registration for the manuscript to be included and published in the proceedings; an author is also expected to attend and present the paper at the Symposium.

Journal Special Issue: Selected papers will have the opportunity to submit an extended version of their work presented at the symposium in a special issue of an archival journal.

Best Paper Award: A "Best Paper Award" will be awarded by the technical program committee.

Prospective authors should adhere to the following deadlines:

Submission deadline:	May 7, 2008
Notification of acceptance:	June 20, 2008
Camera ready full papers:	July 14, 2008

For general information, contact the General co-Chairs. For paper submission information, contact the Program co-Chairs. For all updated information concerning the symposium, visit our Web page.

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